

Joint ICTP-IAEA Advanced Workshop on Portable X-Ray Spectrometry  
Techniques for Characterization of Valuable Archaeological/Art Objects |  
(smr 3298)

Contribution ID : 54

Type : not specified

## Practical Demonstration 12: Measurement of glass and enamel using micro-XRF

*Thursday, 13 June 2019 11:30 (0:45)*

**Content**

**Summary**

**Presenter(s)** : MIGLIORI, A. (IAEA); GRIESSER, M. (Kunsthistorisches Museum Vienna)

**Session Classification** : notitle